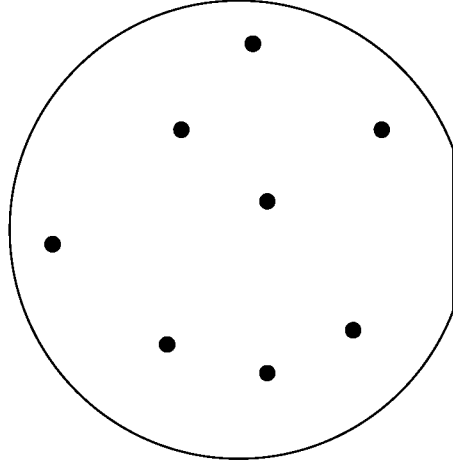
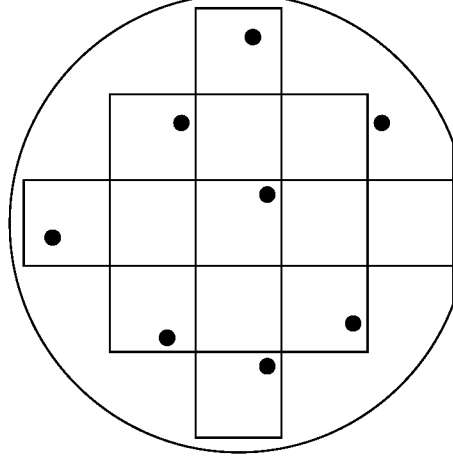


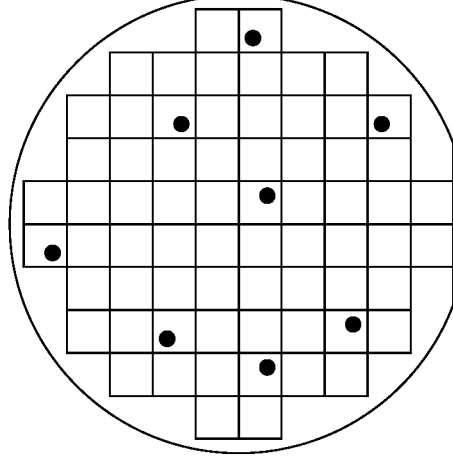
Smaller Die Size: Higher Yield



POINT DEFECTS
RANDOMLY DISTRIBUTED
OVER WAFER



$N = 13$ die
6 good
 $Y = 6/13 = 46\%$



$N = 68$
60 good
 $Y = 60/68 = 88\%$